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TABLE OF CONTENTS

Single Event Effects on a Dual Narrow-Band and Wideband RF Agile Transceiver	1
<i>Jan Budroweit, Ferdinand Stehle, Felix Eichstaedt</i>	
X-Ray Impact on Analog References in 110 nm ST BCD9s Technology	5
<i>A. Benfante, D. Crippa, A.M. Veggetti, S. Mattiazzo, M. Bagatin, S. Gerardin</i>	
Temperature Dependence of High Dose Rate Silicon Diode Gamma Detectors	9
<i>K. Stoev, E. Simova</i>	
Design and Radiation Qualification of a New User Interface for the LHC Beam Interlock System	13
<i>Raffaello Secondo, Antoine Colinet, Salvatore Danzeca, Rudy Ferraro, Gilles Foucard, Giuseppe Lerner Christophe Martin, Ivan Romera Ramirez, Jan Uythoven</i>	
Radiation Evaluation of the TPS7H1121-SP Radiation-Hardened 2.25V to 14V Input, 2A Low Dropout (LDO) Linear Regulator	21
<i>A. Marinelarena, M. Trevino, T. Lew</i>	
Qualification of Gallium-Nitride High Electron Mobility Transistors for the 10 MHz Radio-Frequency systems in the CERN Proton Synchrotron	26
<i>G. Gnemmi, C. Ohmori, S. Energico, M. Paoluzzi, C. Rossi, S. Ramberger</i>	
Heavy ion Single Event Effect Tests of Commercial-off-the-shelf components	32
<i>Michael Steffens, Stefan Höffgen, Jochen Kuhnhehn, Tobias Kündgen, Felix Siebert, Adrian Zentgraf Gianluca Furano, Marc Poizat, Maris Tali</i>	
Evaluation of LGAD Performance Degradation due to TID Aging Under 10 keV X-ray Irradiation	36
<i>T. A. Silva, A. C. Vilas-Bôas, F. R. Palomo, M. A. Pavanello, R. C. Giacomini, N. H. Medina M. A. Guazzelli</i>	
Radiation Characterization of a LEON5FT-based SoC on the DARE65T Platform	41
<i>Lucas Antunes Tambara, Maxim Gorbunov, Marcel van de Burgwal, Laurent Berti, Johan Hellström Ádria Barros de Oliveira, Jan Andersson Nerén</i>	
Total Ionizing Dose and SEE Testing of the TPS7H4012-SP and TPS7H4013-SP 14V Synchronous Buck Converter	46
<i>Kyle Rakos, Anthony Marinelarena</i>	
VSC8574RT Radiation Tolerant, Quad Port, Dual Media Gigabit Ethernet PHY : Single Event Effects and Total Ionizing Dose performances	51
<i>Benjamin Treuillard, Guillaume Bourg-Cazan, Kilian De Saint Jan, Laurence Montagner Philippe Fournier, Florence Malou, David Dangla</i>	
Study of SEE and TID effects According to the Development of NAND Technology	52
<i>Woongki Kim, Dongwoo Bae, Hyeongju Kim, Daeyong Eom, Seungjoo Woo, Keunwoo Lee, Kiseog Kim Joongseob Yang, Gihyun Bae, Youngboo Kim</i>	
Radiation Evaluation of the Texas Instruments TPS7H3024-SP Radiation Hardened Four-Channel Supervisor with Watchdog	56
<i>T. Lew, J. Cruz-Colon, A. Marinelarena, S. Khan</i>	

Total Ionizing Dose Characterization of Microchip Programmable Current Limiting Power Switch LX7712	62
<i>Russell Stevens, Dorian Johnson</i>	
TID and SEE response of the INA129U Instrumentation Amplifier	67
<i>J. Cardenas Chavez, D.M. Hiemstra, B. Saha, A. Noguera Cundar, L. Chen</i>	
TID Response Characterization of the LP2951 Low Dropout Voltage Regulator	70
<i>A. Noguera Cundar, D.M. Hiemstra, J. Cardenas Chavez, D. Feist, L. Chen</i>	
Radiation response data of power units for the university small satellite ROMEO	73
<i>Thorben Löffler, Kevin Waizenegger, Jonas Burgdorf, Natascha Anastasia Bonidis, Michael Lengowski Sabine Klinkner</i>	
Correlation Between Interface Engineering and Radiation Resistance of Nanoscale Devices	81
<i>Chang Goo Kang, Su Jin Kim, Yongsu Lee, Jeong Min Park</i>	
TID Effects on Opal Photonic Crystal Films	84
<i>K. Stoev, E. Simova, H. Fudouzi</i>	
Effect of Low Energy Proton Irradiation on Optocoupler Performance: Analysing the Role of Packaging	88
<i>Amor Romero-Maestre, José de-Martín-Hernández, Pedro Martín-Holgado, Manuel Dominguez Bob Campanini, Yolanda Morilla</i>	
ATA6571 Radiation Tolerant CAN FD Transceiver With High-Voltage WAKE Pin : Single Event Effects and Total Ionizing Dose Performances	95
<i>Jean-Guy Bernard, Guillaume Bourg-Cazan, Kilian De Saint Jan, Florence Malou, David Dangla Hugo Meneu, Eric Leduc</i>	
TID response characterization of COTS Operational Amplifiers	96
<i>Manasi Sharma, A. Noguera Cundar, D.M. Hiemstra, J. Cardenas Chavez, L. Chen</i>	
A Radiation-hardened Time-to-Digital Converter chip with 8 ps Single-Shot Precision	99
<i>B. Van Bockel, N. Jadhav, D. Hendrickx, Y. Cao, H. Marien</i>	
Guide to the 2024 RADECS Radiation Effects Data Session	103
<i>David M. Hiemstra</i>	
SEE and beam characterization with high-energy heavy ions at HIMAC	107
<i>Matteo Cecchetto, Kacper Bilko, Natalia Emriskova, Rubén García Alía, Satoshi Kodaira, Jean-Luc Autran</i>	
Effect of temperature on SEEs in SiGe HBT exposed to proton and heavy ion beams	115
<i>Jinxin Zhang, Wojciech Hajdas, Xin Wang, Mike C. Gantert, Hongxia Guo, Hui Wang, Yunyi Yan</i>	
SEE Characterization of the 4 Tb 3DFN4T16LB1862 and 8 Tb 3DFN8T16LB2821 3D NAND flash memories for space application	119
<i>P. Kohler, A. L. Bosser, A. Sellaï, P.-X. Wang</i>	
LM5113-Q1 SEE Radiation Test Report	123
<i>Thomas Giroud, Bram Vandoren</i>	
Characterisation of AMD Versal FPGA Transceivers Under Heavy-Ion Radiation	128
<i>Alberto Gonzalez Villafranca, Albert Ferrer Florit, Marti Farras Casas, Steve Parkes, Pierre Maillard Ken O'Neill</i>	

Heavy Ion SEE Results of Analog Devices μ Module DC/DC Converters	133
<i>Anup P. Omprakash, Maggie E. Byers, Barry Liu, Manuel Herrera, Fred Lara, Anthony Huynh</i>	
<i>Ko Kobayashi, Filmore Biacan</i>	